



Sheet 1 of 1

| Form PTO-1449 (REV. 8-83) | | | US Dept. of Commerce PATENT & TRADEMARK OFFICE | | ATTY DOCKET NO. 106298.01 | | APPLICATION NO. 10/726,686 | |
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| INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) | | | APPLICANTS Hidemitsu ASANO et al. | | | | | |
| | | | FILING DATE December 4, 2003 | | GROUP 2613 | | | |
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| EXAMINER <i>A. Rao</i> | | | | DATE CONSIDERED <i>12/20/07</i> | | | | |
| Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | | | | | | | | |

| Form PTO-1449 (REV. 8-83) | | US Dept. of Commerce PATENT & TRADEMARK OFFICE | ATTY DOCKET NO. 106298.01 | Rule 53(b) Continuation-In-Part Application of U. S. Patent Application No. 09/579,009 filed May 26, 2000 | | |
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